

Search Notes

Application/Control No.

10/760,615

Examiner

Jinhee J. Lee

Applicant(s)/Patent under
Reexamination

PERKINS ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
174	66	7/28/2006	LEE
174	66,480	4/30/2007	LEE
439	532,535	↓	↓
VI	536		
361	732		LEE

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
174	as above	7/28/2006	LEE
174,439	as above	4/30/2007	LEE
361	as above	VI	LEE

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached text search	7/28/2006	LEE